## ABSTRACT

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2	A manufacturing process of memory module with direct die-attachment is provided
3	to integrate the process of packaging, module assembling and testing. When a
4	plurality of memory chips are singulated from a wafer, a determined amount of the
5	memory chips are directly mounted to a module substrate, and electrically connected
6	to gold fingers of the module substrate. The module substrate mounting the
7	memory chips is loaded in a memory module tester. The memory chips are tested
8	to verify their electrical performance by contacting the gold fingers, and then the bad
9	ones are repaired or replaced before packaging the memory chips. The
10	manufacturing process of memory module with direct die-attachment can reduce the
11	investment of testers and also the cost of testing.
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